

|   |  |   |
|---|--|---|
| <b>Search Notes</b><br> | <b>Application/Control No.</b><br>10/659,568 | <b>Applicant(s)/Patent under Reexamination</b><br>CHEN ET AL. |
|   | <b>Examiner</b><br>Amelia Rutledge           | <b>Art Unit</b><br>2176                                       |
|   |  |   |

| SEARCH NOTES<br>(INCLUDING SEARCH STRATEGY)  |           |      |
|--|-----------|------|
|  | DATE      | EXMR |
| EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) - See Search History Printout | 2/15/2006 | AR   |
| ACM Digital Library search - see search printouts                                      | 2/15/2006 | AR   |
| IEEE Xplore database search  | 2/15/2006 | AR   |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |
|  |           |      |

| <b>INTERFERENCE SEARCHED</b> |                 |             |                 |
|------------------------------|-----------------|-------------|-----------------|
| <b>Class</b>                 | <b>Subclass</b> | <b>Date</b> | <b>Examiner</b> |
|                              |                 |             |                 |
|                              |                 |             |                 |
|                              |                 |             |                 |
|                              |                 |             |                 |
|                              |                 |             |                 |